

ICS 31.2
CCS L 56



**NATIONAL STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

GB/T 14862-1993

**Junction-to-case thermal resistance test methods of packages
for semiconductor integrated circuits
(English Translation)**

Issued on: December 30, 1993

Implemented on: October 1, 1994

Issued by: State Bureau of Technical Supervision

Table of Contents

What this standard covers	1
Document data	2
Standards quoted by this document	3

What this standard covers

This standard specifies the semiconductor integrated circuit package junction to case thermal resistance test methods. This standard applies to semiconductor integrated circuit ceramic, metal, plastic packaging junction to case thermal resistance measurements.

Document data

International classification (ICS): 31.2.

Chinese classification (CCS): L56.

Estimated length of the Chinese original: 10,142 words.

Standards quoted by this document

GB/T 14113; GJB 548